

Characterization of air terminal device noise using acoustic 1-port source models

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О выборе полосы пропускания измерителя низкочастотных шумов

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Цифровой фильтр для измерения низкочастотных шумов

Siem, L.; **Mägi, Harri** XX студенческая научно-техническая конференция вузов Прибалтийских республик, Белорусской ССР и Молдавской ССР : тезисы докладов. Часть 1 1974 / с. 121 https://www.ester.ee/record=b1306141*est